	Notice	of References	Cited
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Application/Control No.	Applicant(s)/Pater	nt Under	
10/550,529	Reexamination HIRANO ET AL.		
Examiner	Art Unit		
OMONIYI A OBAYANJU	2617	Page 1 of 1	

U.S. PATENT DOCUMENTS

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0214928	11-2003	Chuah, Mooi Choo	370/336
*	В	US-2002/0126692	09-2002	Haartsen, Jacobus	370/450
*	С	US-7,280,518	10-2007	Montano et al.	370/338
*	D	US-7,154,877	12-2006	Le et al.	370/346
	Е	US-			
	F	US-			
	G	US-		-	
	Н	US-		-	
	_	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON DATENT DOCUMENTS

*	* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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